Comparison of two forward solutions approaches in Lorentz Force Evaluation

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Two different forward models for Lorentz force evaluation, the approximate forward solution (AFS) and the novel extended area approach (EAA), are compared using a goal function scan. A laminated aluminum specimen that contains a cuboidal defect of the size 12 mm x 2 mm x 2 mm at 2 mm depth is simulated by the finite element method. Both methods are applied for defect reconstruction and showed a correct depth estimation with normalized root mean square errors (NRMSE) of 6.05 % for AFS and 1.67 % for EAA, respectively. The EAA yields defect dimensions of 11 mm x 2 mm x 2 mm, whereas AFS determines 7 mm x 10 mm x 2 mm.

Index Terms—Eddy current, Lorentz force evaluation, inverse problem, nondestructive evaluation

I. INTRODUCTION

The lorentz force evaluation (LFE) is a nondestructive method, which reconstructs defects from perturbations in Lorentz forces that act on a permanent magnet, which moves relatively to a conductive specimen. Previous defect reconstructions have been performed by truncated singular value decomposition [1], differential evolution [2] and current density reconstruction [3], where all were based on the approximate forward solution (AFS) [1]. Recently, the more accurate extended area approach (EAA) has been introduced as forward model for LFE [4]. It is the aim of the current study to compare the performance of AFS and the novel EAA with regard to defect reconstruction performance. For that purpose, a goal function scan [5] is applied to a simulated dataset obtained by the finite element method (FEM), which is used for modeling a specimen consisting of stacked aluminum sheets and a cuboidal defect.

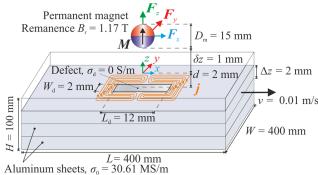


Fig. 1. Benchmark problem: A package of aluminum sheets with a cuboidal defect is moved relatively to the spherical permanent magnet, where the interaction of the induced eddy currents (orange lines) with the magnetic field leads to Lorentz forces; the figure is not to scale for better visualization.

II. METHODS

A. Benchmark problem

A specimen with $L \times W \times H = 400 \text{ mm} \times 400 \text{ mm} \times 100 \text{ mm}$ and the conductivity $\sigma_0 = 30.61 \text{ MS/m}$ is moved relatively to the permanent magnet with the velocity v = 0.01 m/s (Fig. 1). Due to the relative movement eddy currents are induced, where the interaction with the magnetic field leads to Lorentz forces. In presence of a defect these eddy currents are perturbed (Fig. 1) and so are the Lorentz forces. The specimen consists of stacked aluminum sheets, where each sheet possesses a thickness of $\Delta z = 2 \text{ mm}$. The spherical permanent magnet with the homogenous magnetization M is located at the lift-off distance $\delta z = 1 \text{ mm}$ above the top surface of the specimen. It is characterized by a remanence of $B_r = 1.17$ T and a diameter $D_{\rm m} = 15 \,\rm mm$. A cuboidal defect with the conductivity $\sigma_{d} = 0$ S/m and $L_{d} \times W_{d} \times H_{d} = 12$ mm $\times 2$ mm $\times 2$ mm is located at the depth d = 2 mm.

B. Approximate Forward Solution and Extended Area Approach

The spherical permanent magnet is modelled as a magnetic dipole located at its center r_0 . The magnetic flux density at the point r can be calculated by

$$\boldsymbol{B}_{\rm p} = \frac{\mu_0}{4\pi} \left(3 \frac{\left[\boldsymbol{m} \cdot (\boldsymbol{r} - \boldsymbol{r}_0) \right]}{\left| \boldsymbol{r} - \boldsymbol{r}_0 \right|^5} (\boldsymbol{r} - \boldsymbol{r}_0) - \frac{\boldsymbol{m}}{\left| \boldsymbol{r} - \boldsymbol{r}_0 \right|^3} \right), \tag{1}$$

where m denotes the magnetic moment. Due to the small velocity v, the secondary magnetic field from the induced eddy currents can be neglected. Thus, the weak reaction approach can be applied [6].

The defect response signal (DRS) ΔF [4], which forms the basis for the defect reconstruction is defined by

$$\Delta F = \int_{V-V_{\rm d}} (j - j_0) \times B_{\rm p} dV - \int_{V_{\rm d}} j_0 \times B_{\rm p} dV , \qquad (2)$$

where j and j_0 represent the current density in the specimen with and without a defect, respectively. The volumes of the specimen and the defect are denoted by V and V_{d} .

The AFS neglects the first term of (2), which means that only the defect as a fictitious conducting region is taken into account for the calculation of the DRS. The defect is discretized into *K* volume elements (voxels) of volume $V_{\rm E}$. The DRS is then approximated by [1]

$$\Delta \boldsymbol{F}_{\text{AFS}} = V_{\text{E}} \sum_{k=1}^{K} \Delta \boldsymbol{j}_{k} \times \boldsymbol{B}_{k} \quad . \tag{3}$$

The distortion current density $\Delta \mathbf{j}_k = -\mathbf{j}_0$ can be calculated by Ohm's law for moving conductors $\Delta \mathbf{j}_k = -\sigma_0 (-\nabla \varphi_k + \mathbf{v} \times \mathbf{B}_k)$ [1], where \mathbf{B}_k denotes the magnetic flux densities inside the voxels. The EAA extends the region for forward calculation in x – and y – direction around the defect, which approximates the first term of (2). The extended area is discretized into E cuboidal voxels. Thus $\Delta \mathbf{F}$ is approximated by [4]

$$\Delta F_{\text{EAA}} = V_{\text{E}} \sum_{e=1}^{E} \Delta j_e \times \boldsymbol{B}_e + \Delta F_{\text{AFS}}, \qquad (4)$$

where the magnetic flux densities inside the extended voxels are denoted by B_e . The distortion current densities Δj_e in the outer voxels can be determined by [4]

$$\Delta \mathbf{j}_{e} \cong C_{d} \frac{V_{E}}{2\pi\Delta z} \sum_{k=1}^{K} \left[2 \frac{\Delta \mathbf{j}_{k} \cdot (\mathbf{r}_{e} - \mathbf{r}_{k})}{|\mathbf{r}_{e} - \mathbf{r}_{k}|^{4}} (\mathbf{r}_{e} - \mathbf{r}_{k}) - \frac{\Delta \mathbf{j}_{k}}{|\mathbf{r}_{e} - \mathbf{r}_{k}|^{2}} \right],$$
(5)

where the dipolar correction factor $C_d = 1 + (\pi/4)(L_d/W_d)$ holds for cuboidal defects [4]. The position vectors of the voxels' centroids in the defect and the extended region are denoted by r_k and r_e , respectively.

For the EAA, the decision of an appropriate expansion size is important. The DRS ΔF_{EAA} is calculated for the benchmark problem for the extensions $ex = [0, 1, 2, ..., 7] \cdot \max(L_d, W_d)$ in $\pm x$ – and y – direction, where 0 means AFS is applied. The expansion has been chosen to $ex = 5 \cdot \max(W_d, L_d)$ as the adapted normalized root mean square error (*aNRMSE*)—stopped improving.

C. Goal Function Scan

The DRS is calculated by AFS according to (3) and by EAA according to (4), respectively, for the combinations of $L_d = [1, 2, ..., 50 \text{ mm}]$ and $W_d = [1, 2, ..., 50 \text{ mm}]$ from the 1st to the 11th layer. For each calculation, the *aNRMSE* is determined as a goal function value by *aNRMSE* =

$$\frac{1}{2} \sum_{i=x,z} \left[\frac{\sqrt{\frac{1}{N} \sum_{n=1}^{N} \left(\Delta F_{n,i}^{AFS/EAA} - \Delta F_{n,i}^{FEM} \right)^{2}}}{\min \left[\left(\max_{n=1...N} \Delta F_{i}^{AFS/EAA} - \min_{n=1...N} \Delta F_{i}^{AFS/EAA} \right), \left(\max_{n=1...N} \Delta F_{i}^{FEM} - \min_{n=1...N} \Delta F_{i}^{FEM} \right) \right]} \right], (6)$$

where *n* indicates the current position of the magnetic dipole. Only the *x* – and *z* – error components are used since the *y* – component of the DRS shows too large errors for both forward models. For every aluminum layer, the $L_d - W_d$ -combination with the lowest *aNRMSE* is determined for AFS and EAA. The layer with the lowest *aNRMSE* gives the result for the depth and the size of the defect produced by the goal function scan for AFS and EAA.

III. RESULTS AND DISCUSSION

Fig. 2 shows the *aNRMSE* and the corresponding estimated defect extensions $L_d \times W_d$ in x- and y- direction in mm² (indices, Fig.2) over the aluminum layers for AFS and EAA. It can be observed that both methods determine the defect depth at layer 2 correctly, whereas AFS reconstructs a size of $7 \text{ mm} \times 10 \text{ mm} \times 2 \text{ mm}$ and EAA of $11 \text{ mm} \times 2 \text{ mm} \times 2 \text{ mm}$, respectively.

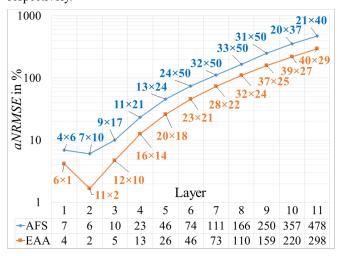


Fig. 2. Results of the goal function scan based on AFS and EAA for a cuboidal defect with x - y – extension (12×2) mm² at the depth 2 mm: The minimal *aNRMSE* and its corresponding estimated defect extension ($L_d \times W_d$) mm² are shown for each layer. The correct defect depth (layer 2) has been found for both forward solutions, whereas the EAA estimates the defect shape more accurately. The rounded *aNRMSE* values are shown in the table.

IV. CONCLUSION

The comparison of AFS and EAA for LFE based on a goal function scan shows that correct defect depth can be estimated with both methods, whereas a better shape reconstruction can be achieved by using the EAA. Current work focuses on the application of the EAA to measurement data.

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